ESTISCO

Noise-Resilient Quantum Simulation with Quantum Error Detection Code

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 $\xrightarrow{\text{mapping}} \tilde{H}$, where

Assumptions and Notations

We create circuits with extra ancillas to protect exp(−*iθ*P) under [[*n, n* − 2*,* 2]] code

- **Assumptions.** We consider gate based Pauli noise but noiseless encoding, decoding and mid-circuit syndrome measurements. We perform analysis on fully connected hardware and assume that the delay due to mid-circuit syndrome measurements will not bring any error during idle time.
- Notation. \overline{P} for the logical operator and P for physical operator corresponding to $\overline{\mathcal{P}}$. *I*, *X*, *Y*, *Z* are single qubit Pauli operators.

- For fermionic system simulation, convert the Hamiltonian into Pauli form using Jordan-Wigner, Bravyi-Kitaev or parity mapping to achieve *H* $\tilde{H} = \sum_j \alpha_j \tilde{P}_j.$
- Use product formula approach to obtain $e^{-i\theta \tilde{H}} \simeq \prod_j e^{-i\theta_j \mathcal{P}_j}$ where $\theta_j = \alpha_j \delta_j.$
- Some parameterized circuits (e.g., QAOA and UCC ansatz) also have similar structure.
- Create circuits in the following form:

Circuits with Exponential Operations

Previous research (not yet published) from Todd Brun and Christopher Gerhard purposes a weakly fault-tolerant construction shown in Fig. 2 that helps detect most single- and two-qubits Pauli noise, except for *X* error at location *d* and *Z* error at location *f*, both of which relate to imprecise rotation angle $\theta + \Delta\theta$.

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|\psi_0\rangle
$$
 \rightarrow $e^{-i\theta_1 P_1}$ $e^{-i\theta_2 P_2}$ \cdots $e^{-i\theta_n P_n}$

Quantum Error Detection Code and Weakly Fault Tolerance

The stabilizer generators are $X^{\otimes n}$ and $Z^{\otimes n}.$ Logical Pauli operators are given by $\overline{X}_i = X_i X_{n-1}, \, \overline{Z}_i = Z_i Z_n$ and $\overline{Y}_i = i \overline{X}_i \overline{Z}_i.$ The logical rotation gates are $\overline{R_{X_i}}(\theta) = \exp\left(-i\right)$ *θ* 2 *XiXn*−¹ \setminus $, \overline{R_{Z_i}}(\theta) = \exp\left(-i\right)$ *θ* 2 *ZiZn*−¹ \setminus

(1)

Below are examples of logical rotations under the [[4*,* 2*,* 2]] code.

Adding ancilla that could decrease the number of remaining logical error at the end of circuit but do not change expected operation.

Figure 1. Circuit of $\overline{R_{X_1}}(\theta) = \exp(-i\theta X_1 X_3/2)$ (left) and $\overline{R_{Z_1}}(\theta) = \exp(-i\theta Z_1 Z_4/2)$ (right).

They are not fault-tolerant, since a Z_3 error occurring at location a becomes a Z_2Z_4 error, and a X_1 error at location *b* becomes a X_1X_4 error, both undetectable.

Create a group of circuits that equivalently implement $\exp(-i\theta\overline{\mathcal{P}})$ with one extra ancilla. Different circuits have different noise-resilient performance.

Weakly Fault Tolerant Rotation

Figure 2. Circuit of weakly fault tolerant $\overline{R_{X_1}}(\theta)$ (left) and $\overline{R_{Z_1}}(\theta)$ (right)

Approach to Construct Noise-Resilient Operation

Inspired by adding ancilla to create weakly fault-tolerance, we purpose four steps to create noise-resilient exponential map $\exp(-i\theta \overline{P})$ with $[[n, n-2, 2]]$ code. Noiseresilience is worse than weakly fault-tolerance but better than doing nothing.

Step 1: Construct Physical Operator

A physical operator of $\exp{(-i\theta\overline{\cal P})}$ can be done by $\exp{(-i\theta\overline{\cal P})} \to \exp{(-i\theta\cal P)},$ where P is physical operator of \overline{P} under [[4, 2, 2]] code.

Step 2: Add ancilla to Physical Operator

number $k = 2$ (left), 6 (middle) and 10 (right).

Step 3: Create Equivalent Circuits

Step 4: Search for Best Noise-Resilient Circuit

Search for circuits with the least remaining logical error (best noise-resilient performance) after syndrome measurement.

Examples

Logical Rotation-*Y*

Figure 3. Two noise-resilient circuits that implement $R_{Y_i}(\theta) = \exp(-i\theta Y_i X_{n-1} Z_n/2)$ in $[[n, n-2, 2]].$

Figure 4. Logical error rate (left) and post-selection rate (right) of two noise-resilient circuits under 1,000,000 trials simulation with depolarizing gate noise.

Logical Exponential with Weight *n >* 3 **Pauli**

Figure 5. Percentage of remaining logical error versus weights in exp(−*iθZ* ⊗*n*) using circuit on the right.

With Mid-Circuit Syndrome Measurement

Protocol

Use noise-resilient circuit for exp(−*iθ*P) and measure syndromes after each layer.

Performance Under Error Rate *p* **with** *k* **Logical Qubits**

Figure 6. Performance with different number of $\exp(-i\theta Z^{\otimes n})$ layer $(n = k + 2)$ with $p = 10^{-5}$ (left), 10^{-3} (middle) and 5×10^{-3} (right).

Figure 7. Performance with different number of exp(−*iθZ* ⊗*n*) layer (*n* = *k* + 2) with logical qubits

Comments

- \blacksquare Optimize near term resources by using fewer qubits and $\mathcal{O}(2n)$ CNOTs.
- Reduce overhead by discarding noisy shots and no need for correction compare with QEC. ■ Can be used on near-term small-sacle fermionic system simulation.
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Required device with full connectivity to achieve optimal performance (e.g, ion trap system) Required device with perfect qubit reset to achieve best mid-circuit measurement.

